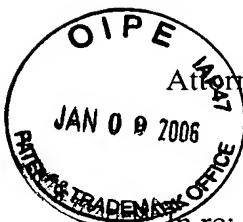


IFW



Attorney Docket No. 5649-1276

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Young-pil Kim et al.

Serial No.: 10/796,672

Filed: March 9, 2004

For: **Semiconductor Device Test Patterns and Related Methods for Precisely Measuring Leakage Currents in Semiconductor Cell Transistors**

Examiner: Matthew C. Landau
Group Art Unit: 2815
Confirmation No.: 3015

Date: January 6, 2006

Mail Stop AMENDMENT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE TO RESTRICTION/ELECTION REQUIREMENT

Sir:

In response to the Restriction Requirement included in the Office Action mailed December 9, 2005, Applicants hereby elect the invention of **Invention I** which is drawn to Claims 1-16 and 41-42. In response to the Election Requirement included in the Office Action mailed December 9, 2005, Applicants hereby provisionally elect the species depicted in FIG. 5, which encompasses Claims 1-7, 9 and 41-42.

It is not believed that an extension of time and/or additional fee(s), including fees for net addition of claims-are required, beyond those that may otherwise be provided for in documents accompanying this paper. In the event, however, that an extension of time is necessary to allow consideration of this paper, such an extension is hereby petitioned under 37 C.F.R. §1.136(a). Any additional fees believed to be due in connection with this paper may be charged to our Deposit Account No. 50-0220.